Unit: mm

TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (DTMOS)

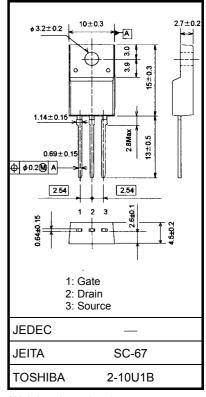
TK20A60U

Switching Regulator Applications

- Low drain-source ON-resistance: RDS (ON) = 0.165Ω (typ.)
- High forward transfer admittance: $|Y_{fs}| = 12 \text{ S (typ.)}$
- Low leakage current: $I_{DSS} = 100 \ \mu A \ (V_{DS} = 600 \ V)$
- Enhancement-mode: $V_{th} = 3.0$ to 5.0 V ($V_{DS} = 10$ V, $I_D = 1$ mA)

| Characteristics | | Symbol | Rating | Unit | |
|---|------------------------------|------------------|------------|------|--|
| Drain-source voltage | | V _{DSS} | 600 | V | |
| Gate-source voltage | | V _{GSS} | ±30 | V | |
| Drain current | DC (Note 1) | ID | 20 | | |
| | Pulse (t = 1 ms) (Note 1) | I _{DP} | 40 | A | |
| Drain power dissipati | on (Tc = 25°C) | PD | 45 | W | |
| Single pulse avalanche energy (Note 2) | | E _{AS} | 144 | mJ | |
| Avalanche current (Note 3) | | I _{AR} | 20 | А | |
| Repetitive avalanche energy | | E _{AR} | 4.0 | mJ | |
| Channel temperature | | T _{ch} | 150 | °C | |
| Storage temperature range | | T _{stg} | -55 to 150 | °C | |

Absolute Maximum Ratings (Ta = 25°C)



Weight : 1.7 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Thermal Characteristics

| Characteristics | Symbol | Max | Unit |
|--|------------------------|------|------|
| Thermal resistance, channel to case | R _{th (ch-c)} | 2.78 | °C/W |
| Thermal resistance, channel to ambient | R _{th (ch-a)} | 62.5 | °C/W |

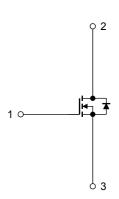
Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2: V_{DD} = 90 V, T_{ch} = 25°C (initial), L = 0.63 mH, R_G = 25 Ω , I_{AR} = 20 A

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device. Handle with care.

Internal Connection



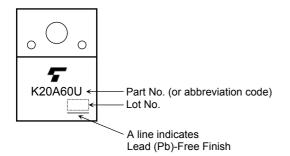
Electrical Characteristics (Ta = 25°C)

| Char | acteristics | Symbol | Test Condition | Min | Тур. | Max | Unit |
|--------------------------------|---------------|----------------------|---|-----|-------|------|------|
| Gate leakage current | | I _{GSS} | $V_{GS}=\pm 30~V,~V_{DS}=0~V$ | | — | ±1 | μA |
| Drain cut-off current | | I _{DSS} | $V_{DS} = 600 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$ | _ | _ | 100 | μA |
| Drain-source breakdown voltage | | V (BR) DSS | $I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$ | 600 | _ | | V |
| Gate threshold v | oltage | V _{th} | $V_{DS} = 10 \text{ V}, \text{ I}_{D} = 1 \text{ mA}$ | 3.0 | _ | 5.0 | V |
| Drain-source ON | I-resistance | R _{DS (ON)} | $V_{GS} = 10 \text{ V}, \text{ I}_{D} = 10 \text{ A}$ | _ | 0.165 | 0.19 | Ω |
| Forward transfer | admittance | Y _{fs} | $V_{DS} = 10 \text{ V}, \text{ I}_{D} = 10 \text{ A}$ | 3 | 12 | _ | S |
| Input capacitance | | C _{iss} | | _ | 1470 | _ | |
| Reverse transfer capacitance | | C _{rss} | V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz | | 150 | _ | pF |
| Output capacitance | | C _{oss} | | | 3500 | | |
| Switching time | Rise time | tr | $\begin{array}{c} 10 \text{ V} \\ \text{V}_{GS} \\ 0 \text{ V} \\ 50 \Omega \\ \end{array} \begin{array}{c} \text{I}_{D} = 10 A \\ \text{V}_{OUT} \\ $ | _ | 40 | | . ns |
| | Turn-on time | t _{on} | | | 80 | | |
| | Fall time | t _f | | _ | 12 | _ | |
| | Turn-off time | t _{off} | | | 100 | _ | |
| Total gate charge | | Qg | | | 27 | | |
| Gate-source charge | | Q _{gs} | $V_{DD} \approx 400 \text{ V}, \text{ V}_{GS} = 10 \text{ V}, \text{ I}_{D} = 20 \text{ A}$ | _ | 16 | — | nC |
| Gate-drain charge | | Q _{gd} | 1 | — | 11 | — | |

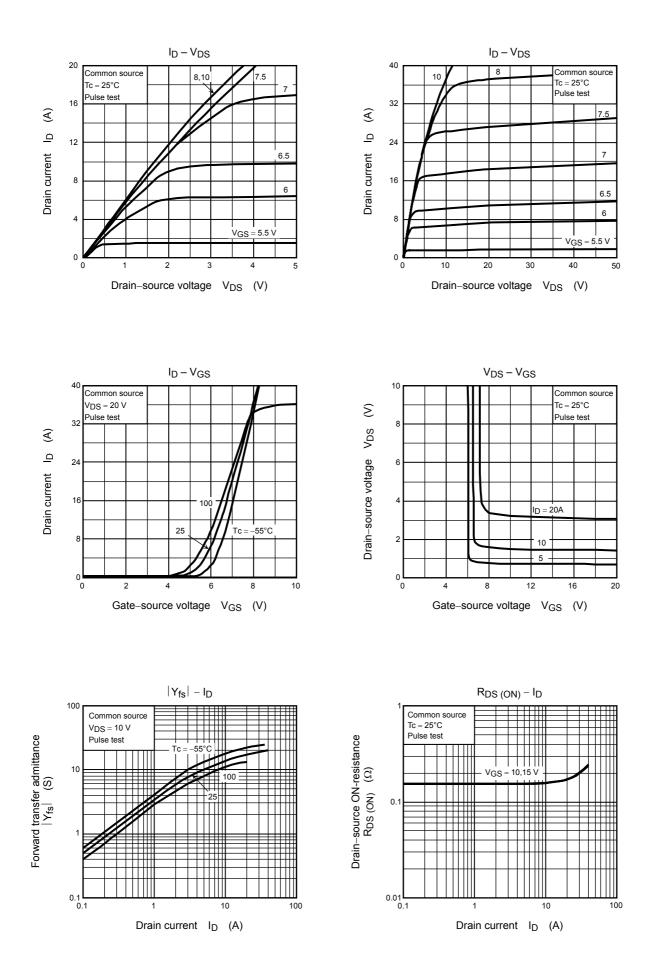
Source-Drain Ratings and Characteristics (Ta = 25°C)

| Characteristics | Symbol | Test Condition | Min | Тур. | Max | Unit |
|---|------------------|--|-----|------|------|------|
| Continuous drain reverse current (Note 1) | I _{DR} | — | _ | _ | 20 | А |
| Pulse drain reverse current (Note 1) | I _{DRP} | — | _ | _ | 40 | А |
| Forward voltage (diode) | V _{DSF} | $I_{DR} = 20 \text{ A}, V_{GS} = 0 \text{ V}$ | _ | _ | -1.7 | V |
| Reverse recovery time | t _{rr} | $I_{DR} = 20 \text{ A}, V_{GS} = 0 \text{ V},$ | _ | 450 | _ | ns |
| Reverse recovery charge | Q _{rr} | dl _{DR} /dt = 100 A/μs | _ | 8.1 | _ | μC |

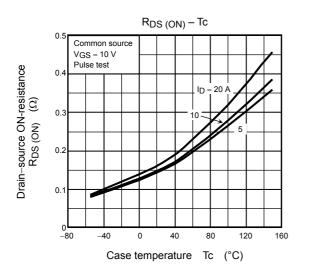
Marking

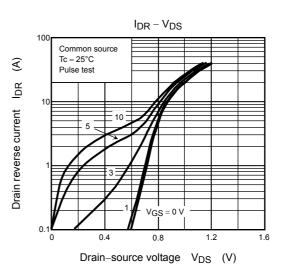


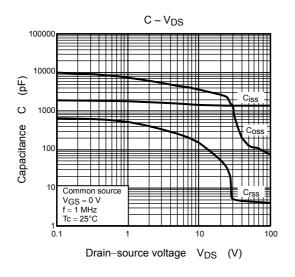
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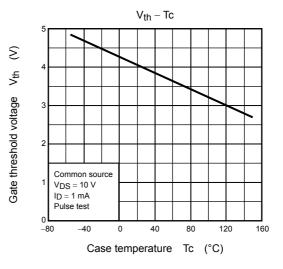


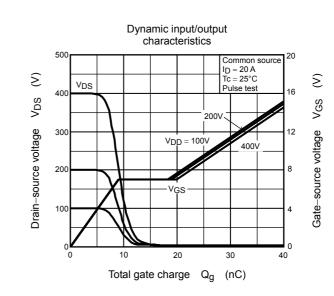
TOSHIBA

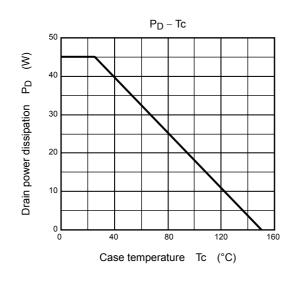


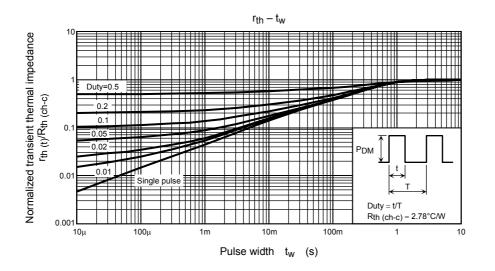




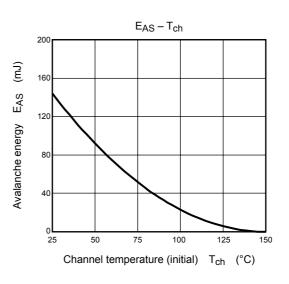


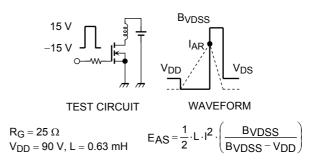






Safe operating area 100 ID max (Pulse) 100 μs ID max (Continuo 1(ms $\overline{\mathsf{A}}$ Drain current I_D DC operation Тс 25°C lΠ 0. Single nonrepetitive pulse Tc = 25°C 0.01 Curves must be derated linearly with increase in temperature. VDSS ma 0.001 0.1 10 100 1000 1 Drain-source voltage V_{DS} (V)





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